

<b>Notice of References Cited</b>	Application/Control No. 10/622,029	Applicant(s)/Patent Under Reexamination TAKIZAWA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,678,867	01-2004	Fong et al.	715/523
*	B	US-2003/0140316	07-2003	Lakritz, David	715/536
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

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